

ABSTRACT OF THE DISCLOSURE

In order to provide a simple method for manufacturing a more finely detailed split probe with less damage being incurred, by tilting the whole of the microcantilever 6, it is possible to easily determine the center of the probe tip and decide processing position. Channel processing 1 and 2 is carried out using a small focused ion beam current over an extremely narrow range of the processing position. A channel 3 spanning a broad range connected to the channels 1 and 2 is processed using a focused ion beam current larger than the aforementioned focused ion beam current used at the channel processing of the channels 1 and 2, and the electrodes are cut.